

PROFILE SUPPLEMENT FOR LEAD-FREE ALLOYS



This information is provided as a reference guideline only. Your temperature profile will depend upon many factors including customer requirements, component characteristics and restrictions, oven characteristics, board layout, etc. Ultimately, quality requirements should define the profile in use, not adherence to these guidelines.

These reference guidelines follow the recommendations of the standards IPC-7530 for Temperature Profiling for Mass Soldering Processes, IPC-9502 PWB Assembly Soldering Process Guideline for Electronic Components, IPC/EIA J-STD-001 Requirements for Soldered Electrical and Electronic Assemblies and IPC/JEDEC J-STD-020C Requirements for Small to Very Large Bodied Components.

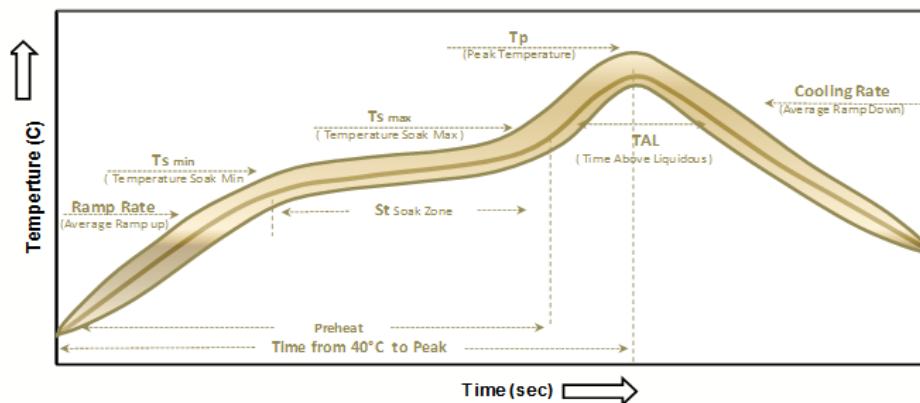
Ideally, temperature profile measurements are to be collected on a populated assembly with the reflow profile recorded for each product being processed. IPC-7050 provides guidelines for the construction of reflow profiling test vehicles and various techniques for reflow temperature profiling. It is common for the same profile settings to be used for multiple assemblies. It is recommended that profile data should be collected, analyzed and recorded for each assembly part number at the beginning of individual production runs for process verification and record keeping.

REFLOW SOLDERING PROFILE DEVELOPMENT

The reflow temperature profile is defined by the relationship of temperature versus time during heating. There are two basic temperature profile types: Ramp-Soak-Spike (RSS) and Ramp-to-Spike (RTS). The RTS temperature profiles are suitable for use in most applications for enhanced solder performance. RSS temperature profiles are appropriate when the assembly has a large thermal mass or large ΔT .

The profile should be cross referenced with component manufacturer recommendations to ensure the maximum temperature limitations on all materials are not exceeded. It is advisable to verify the thermal sensitivity of components per the supplier specification or refer to IPC-9502, before defining a process and reflow profile.

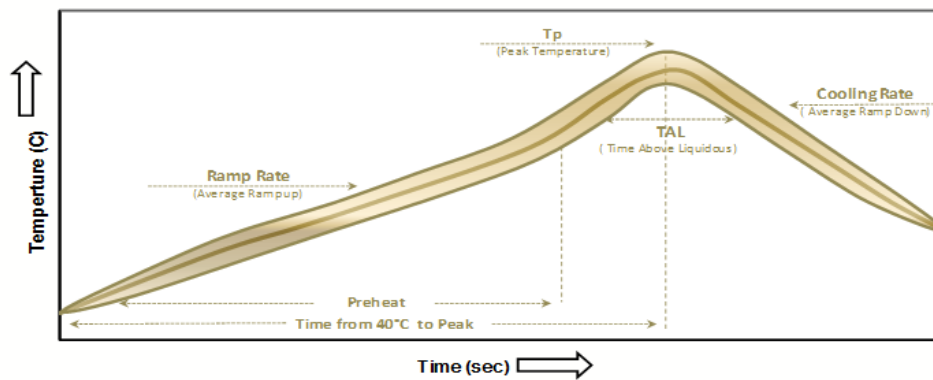
RAMP-SOAK-SPIKE PROFILE (RSS)



RECOMMENDED PARAMETERS FOR RSS

Profile Feature	General Profile IPC/JEDEC ¹	No Clean Flux (Recommended starting point) ²	Water Soluble Flux (Recommended starting point) ³
Ramp Up Rate	< 3°C/sec.	1 - 3°C/sec.	1.5 - 3°C/sec.
Soak Zone Ts min - Ts max	150°C-200°C	150°C-200°C	140°C-160°C
Soak Time (Pt)	< 180 sec.	30-90 sec.	15-30 sec.
Time Above Liquidus (TAL) ⁴	30-90 sec.	30-90 sec.	30-90 sec.
Peak Temperature (Tp)	230°C-260°C	230°C-250°C SAC and REL 240°C-260°C SN100C & Low Ag	230°C-250°C SAC and REL 240°C-260°C SN100C & Low Ag
Cooling Rate	< - 6°C/sec.	< - 4°C/sec.	< - 4°C/sec.
Time From 40°C to Peak	< 6 min	3-4.5 min	3-4 min

RAMP-TO-SPIKE PROFILE (RTS)



RECOMMENDED PARAMETERS FOR RTS

Profile Feature	General Profile IPC/JEDEC ¹	No Clean Flux (Recommended starting point) ²	Water Soluble Flux (Recommended starting point) ³
Ramp Up Rate	< 3°C/sec.	1-3°C/sec.	1.5-3°C/sec.
Time Above Liquidus (TAL) ⁴	30-90 sec.	30-90 sec.	30-90 sec.
Peak Temperature (Tp)	230°C-260°C	230°C-250°C SAC and REL 240°C-260°C SN100C & Low Ag	230°C-250°C SAC and REL 240°C-260°C SN100C & Low Ag
Cooling Rate	< - 6 °C/sec.	< - 4 °C/sec.	< - 4 °C/sec.
Time From 40°C to Peak	< 6 min	3-4.5 min	3-4 min

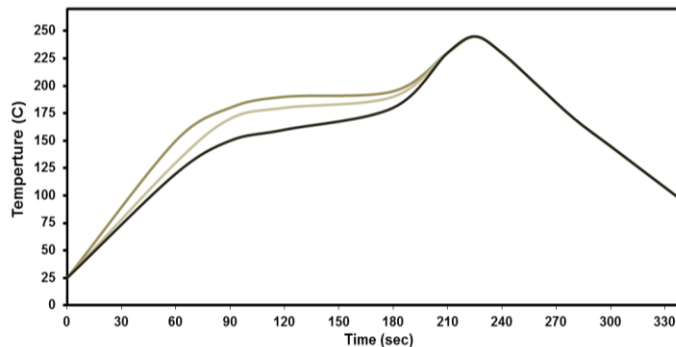
SPECIAL PROFILES

Wetting Improvement

Wetting issues, whether component or substrate may be improved through profiling. If the wetting issue is global, it can often be improved with proper profiling technique. If the wetting issue is component specific, it is likely a plating issue with the component/substrate. Profiling can be manipulated to improve wetting, but may affect other devices on the assembly. A general approach to enhance wetting is to shorten the profile to as little as three (3) minutes and to increase the peak temperature by 10-15°C.

Void Reduction

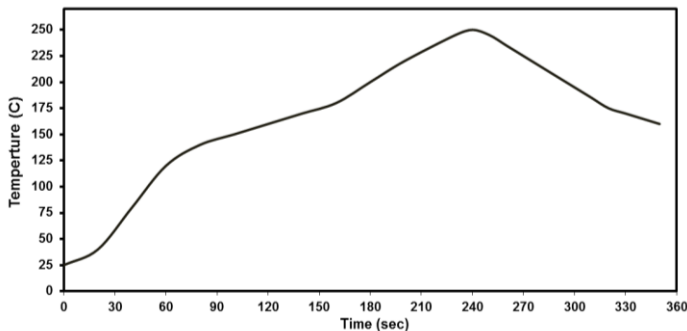
Solder paste is approximately 50% flux by volume and not all of this flux can be evacuated from the solder joint during reflow. Profiling techniques can be used to reduce void formation with modest improvements. Other process variables may have more significant impact.

**Typical Void Reduction Profiles For No Clean Flux**

Ramp Rate to Soak: < 3°C/sec. Typically 1-3°C/sec.
Soak Zone: 150-200°C for < 90 sec. Typically 30 sec.
Time from 40°C to Peak: Typically 3-4.5 minutes.
Time Above Liquidus: 30-90 sec.
Peak Temperature: 230-260°C
Typically 230-250°C. SAC and REL
Typically 240-260°C. SN100C & Low Ag Alloys
Cooling Rate: < - 4°C/sec.

BGA Head-in-Pillow (HiP) Reduction

This profile will help reduce the effects of warpage of plastic BGA packages that leads to HiP defects and may require peak temperature in penultimate heating zone.

**Typical HiP Reduction Profile for No Clean Flux**

Time from 40°C to Peak: 4 - 4.5 minutes
Ramp Rate to Soak: 2-3°C/sec.
Soak Zone: 150-180°C
Soak Time 30-90 seconds.
Ramp Rate Soak to Peak: 1-1.5°C/sec. max.
Peak Temperature: 230-260°C
Typically 230-250°C. SAC and REL
Typically 240-260°C. SN100C & Low Ag Alloys
Time Above Liquidus: > 60 sec.
HiP Cooling Rate: Peak to 210°C, 1-1.5°C/sec. max.
Cool Down Rate After 210°C: < - 4°C/sec.

REFLOW TEMPERATURE PROFILE TROUBLESHOOTING

Issue	Possible Cause														
	Preheat time is too long	Preheat time is too short	Preheat Temperature too high	Preheat temperature too low	Excessive Time Above Liquidus (TAL)	Insufficient Time Above Liquidus (TAL)	Peak Temp Too High	Peak Temp Too Low	Cooling Rate Too Fast	Cooling Rate Too Slow	Profile Too Long	Profile Too Short	Ramp Up Too Fast	Time from 25°C to Peak Temperature too short	Time from 25°C to Peak Temperature too long
Dark residue	✓							✓			✓				
Brittle solder / Cold Solder joint						✓		✓			✓	✓			
Disturbed solder joint										✓					
Component deformation/ damage							✓		✓				✓		
Crazing of residue									✓						✓
De-wetting	✓		✓		✓		✓								✓
Random solder balls		✓		✓		✓					✓	✓			
Grainy solder joints	✓		✓		✓		✓	✓		✓	✓	✓			
Excessive flux residue		✓				✓		✓				✓			
Flux spattering	✓														
Malleable/ weak solder joint					✓			✓		✓					
Poor or non-wetting	✓		✓			✓		✓			✓	✓			✓
Popcorning/ component damage	✓														
Solder spattering	✓	✓		✓									✓		
Thermal shock/ component damage									✓						
Tombstoning		✓	✓	✓					✓						
Voiding		✓		✓		✓		✓							
Wicking solder		✓						✓							
Solder beads	✓														
Head in pillow Hip								✓	✓					✓	

This defect information is specific to potential causes that are reflow profile related. Soldering defects can be caused by a myriad of other process/material variables. Please consult AIM Technical Support for targeted process and profiling assistance. Use of profiles which are outside of the recommended parameters of this supplement due to component temperature restrictions, use of fixtures, or which are heavily populated assemblies may require a profile which is outside of these process windows. Please consult an AIM Technical Support Engineer for assistance.

TERMS AND DEFINITIONS

Alloy, Tin Silver Copper (Sn-Ag-Cu): An alloy that is used as a lead-free solder consisting of tin, silver and copper as the main constituents.*

Alloy, Tin Nickel Copper (Sn-Ni-Cu): An alloy that is used as a lead-free solder consisting of tin and copper considered to be applicable for wave or reflow soldering.

Allowable Temperature: The temperature range that an electronic circuit or component can perform its intended functions.

Component: An individual part or combination of parts that, when together, perform a design function(s).*

Cold Solder: A solder connection that exhibits poor wetting and that is characterized by a grayish, porous appearance caused by insufficient application of heat during the soldering process.

Disturbed Solder Joint: A solder connection that is characterized by the appearance that there was motion between the metals being joined when the solder was solidifying.*

De-Wetting: Retreating of solder from some or all parts of a substrate that initially was wetted.

Flux: A chemically and physically active compound that, when heated, promotes the wetting of a base metal surface by molten solder by removing minor surface oxidation and other surface films and by protecting the surfaces from re-oxidation during a soldering operation.*

Flux Residue: A flux-related contaminant that is present on or near the surface of a solder connection.*

Head-in-Pillow (Hip): Head-in-pillow (HiP), also known as ball-and-socket, is a solder joint defect where the solder paste deposit wets the pad, but does not fully coalesce with the BGA sphere. The resulting solder joint forms enough of a connection to have electrical continuity, but lacks mechanical strength. These components may fail with very little mechanical or thermal stress. This defect is not usually detected in functional testing leading to a field failure.

Liquidus: The temperature at which solder reaches its fully molten or liquid state.

Non-Wetting: A surface that has contacted but rejected molten solder.

Packages: The container for a circuit component, or components that is used to protect its contents and to provide terminals for making connections to the rest of the circuit.*

Peak/Spike Temperature: Peak temperature is the maximum temperature recorded by the thermocouple for the monitored location.

Popcorning: Eruptions in an IC during reflow, normally the result of moisture absorption.

Reflow Profile: The time vs. temperature graph of a PCB as it is processed through a heat source.

Ramp Up: The portion of the profile where the assembly is heated from ambient temperature at a predetermined rate. Controlling the ramp is necessary to prevent thermal component damage.

Preheat / Soak Time: The time is monitored to ensure temperature equilibrium across the assembly. This portion of the profile also allows time to drive off volatile ingredients within the solder paste and activate the paste's flux to remove oxides. Soak Time or Preheat time = t_{smin} to t_{smax} .

Solder Balls: Tiny spheres of solder usually located around a solder joint or randomly around the board.

Solder Beads: A solder ball positioned between the terminations of a discrete component, usually a resistor or capacitor, but can also be found on large and small transistors as well. It is often a function of paste volume as well as reflow profile.

Time Above Liquidus: This is the time in which the solder alloy is in a liquid phase. The assembly must spend enough time in this state to ensure all areas of the assembly are properly reflowed.

Time Above Peak: The time in which the component measured achieves the highest temperature.

Ts Max: Maximum temperature of soak.

Ts Min: Minimum temperature of soak.

Tombstoning: A soldering defect in which a component is pulled into a vertical or angular position leaving one side unsoldered.

Wetting: The formation of an intermetallic allowing the spread of molten solder over a base metal.

Wicking Solder: Wicking is a redistribution of solder caused by molten solder surface tension.

*Quoted from IPC-T-50.

¹The general profile data are the parameters allowable by IPC/JEDEC, and are added only as a reference.

²This data guideline applies only to no clean flux. Special characteristics of flux will be described on TDS of the specific product.

³This data guideline applies only to water soluble flux. Special characteristics of flux will be described on TDS of the specific product.

⁴This temperature applies to most common lead-free alloys (i.e. SAC, SN100C). Special LF alloys should be described on TDS of the specific product.

This document applies to all AIM solder products that reference it on the TDS.

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